# Issue Classification

| Application/Control No. | Applicant(s)/Patent Under Reexamination |
|---|---|
| 10784488 | WEN ET AL. |
| **Examiner** | **Art Unit** |
| Lee, Douglas S | 2125 |

| ORIGINAL | | INTERNATIONAL CLASSIFICATION | | | | | | | | | | |
|---|---|---|---|---|---|---|---|---|---|---|---|---|
| CLASS | SUBCLASS | CLAIMED | | | | | NON-CLAIMED | | | | | |
| 700 | 99 | G | 0 | 6 | F | 19 / 00 | | | | | | |

| CROSS REFERENCE(S) | | | | | |
|---|---|---|---|---|---|
| CLASS | SUBCLASS (ONE SUBCLASS PER BLOCK) | | | | |
| 700 | 28 | 102 | | | |

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|---|---|---|---|
| Douglas S. Lee 3/16/2007<br>(Assistant Examiner) (Date) | LEO PICARD<br>SUPERVISORY PATENT EXAMINER<br>TECHNOLOGY CENTER 2100 | Total Claims Allowed:<br>49 | |
| (Legal Instruments Examiner) (Date) 3/19/07 | Leo Picard<br>(Primary Examiner) (Date) 3/19/07 | O.G. Print Claim(s)<br>1 | O.G. Print Figure<br>3 |